ALPHA & OMEGA SEMICONDUCTOR, LTD

AON3816
Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

The AON3816/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration. AON3816 and AO3816L are electrically identical.

-RoHS Compliant

-AO3816L is Halogen Free

Features

V_{DS} (V) = 20V

I_D = 4A (V_{GS} = 4.5V)

$R_{DS(ON)}$ < 22mΩ (V_{GS} = 4.5V)

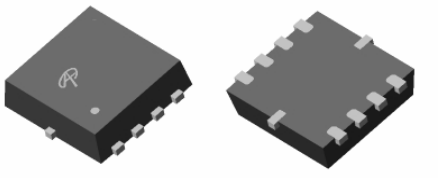
$R_{DS(ON)}$ < 23mΩ (V_{GS} = 4V)

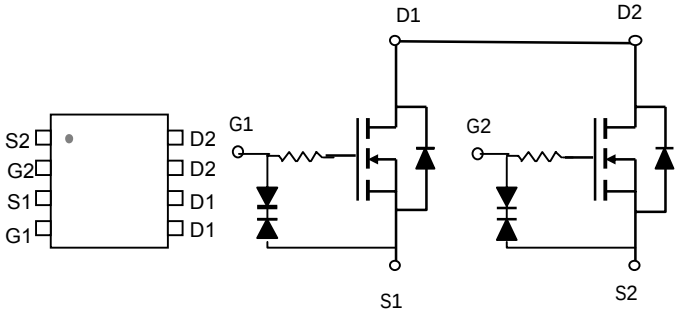
$R_{DS(ON)}$ < 28mΩ (V_{GS} = 2.5V)

ESD Protected

DFN 3x3

Top View **Bottom View**





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	10 Sec	Steady State	Units
Drain-Source Voltage		V_{DS}	20		V
Gate-Source Voltage		V_{GS}	±12		V
Continuous Drain Current [A F]	T_A=25°C	I_D	4	4	A
	T_A=70°C		4	4	
Pulsed Drain Current [B]		I_{DM}	20		
Power Dissipation [A]	T_A=25°C	P_D	2.4	1.4	W
	T_A=70°C		1.5	0.9	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	43	52	°C/W
Maximum Junction-to-Ambient [A]	Steady State		80	90	°C/W
Maximum Junction-to-Lead [C]	Steady State	$R_{\theta JL}$	33	50	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	20			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=20V, V_{GS}=0V			1	µA
		T_J=55°C			5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}=±10V			10	µA
BV_{GSO}	Gate-Source Breakdown Voltage	V_{DS}=0V, I_G=±250µA	±12			V
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	0.4	0.75	1.1	V
$I_{D(ON)}$	On state drain current	V_{GS}=4.5V, V_{DS}=5V	20			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=4.5V, I_D=4A	14	18	22	mΩ
		T_J=125°C	18	23	29	
		V_{GS}=4V, I_D=4A	15	19	23	mΩ
		V_{GS}=2.5V, I_D=4A	17	22.5	28	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=4A		21		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				3	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=10V, f=1MHz		1315		pF
C_{oss}	Output Capacitance			219		pF
C_{rss}	Reverse Transfer Capacitance			183		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		2.1		kΩ
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	V_{GS}=4.5V, V_{DS}=10V, I_D=4A		15		nC
Q_{gs}	Gate Source Charge			6.7		nC
Q_{gd}	Gate Drain Charge			4.6		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=5V, V_{DS}=10V, R_L=2.5Ω, R_{GEN}=3Ω		1		µs
t_r	Turn-On Rise Time			2.8		µs
$t_{D(off)}$	Turn-Off DelayTime			5.6		µs
t_f	Turn-Off Fall Time			5.9		µs

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F. The continuous current rating is limited by wire-bonding.

Rev 2: Feb 15. 2008

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

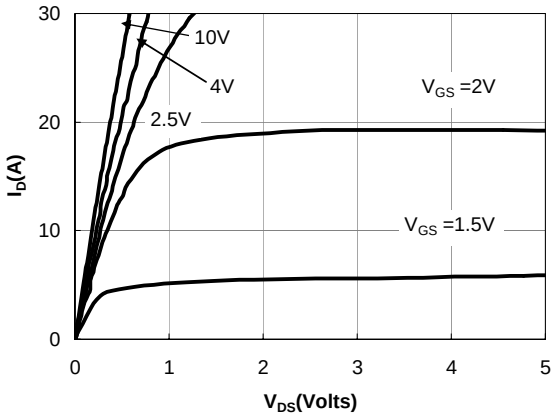


Figure 1: On-Regions Characteristics

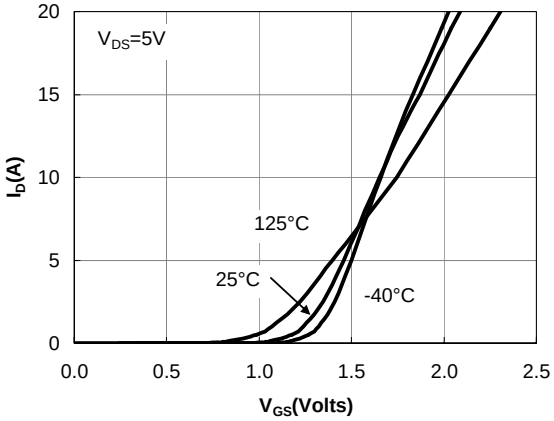


Figure 2: Transfer Characteristics

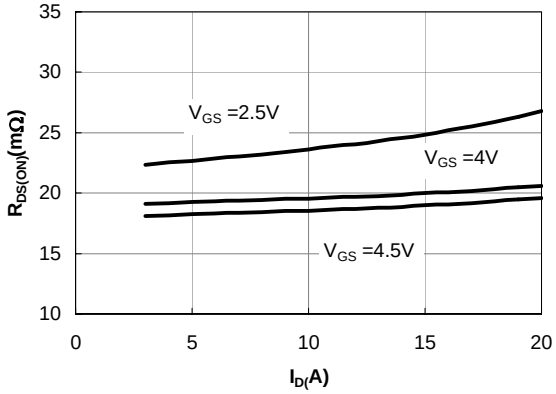


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

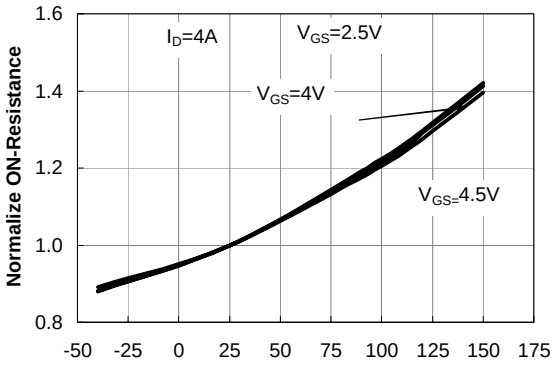


Figure 4: On-Resistance vs. Junction Temperature

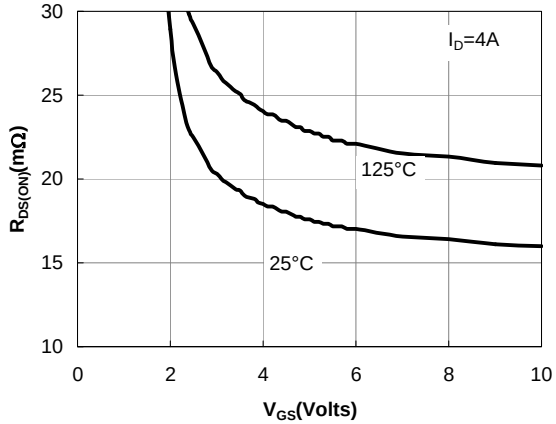


Figure 5: On-Resistance vs. Gate-Source Voltage

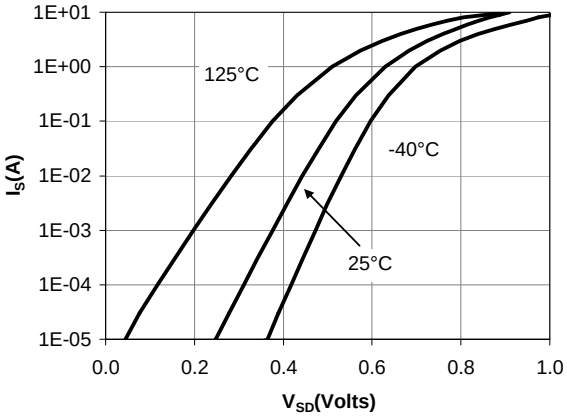


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

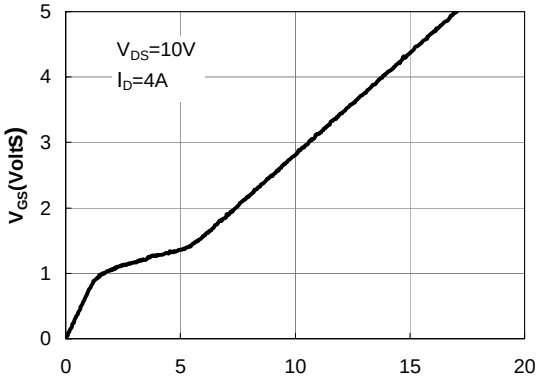


Figure 7: Gate-Charge Characteristics

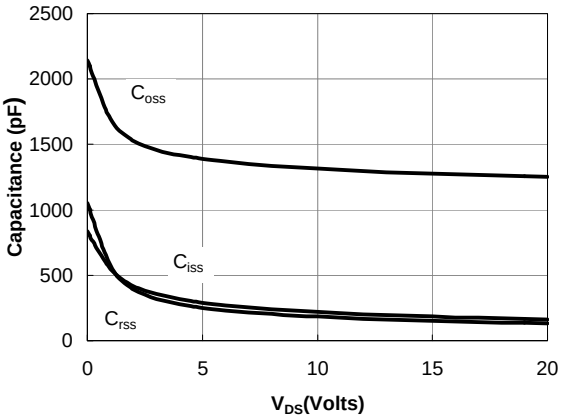


Figure 8: Capacitance Characteristics

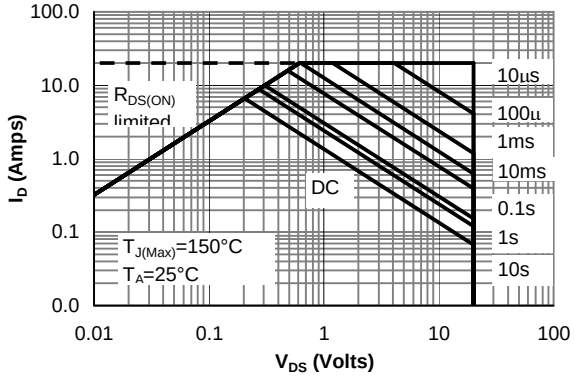


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

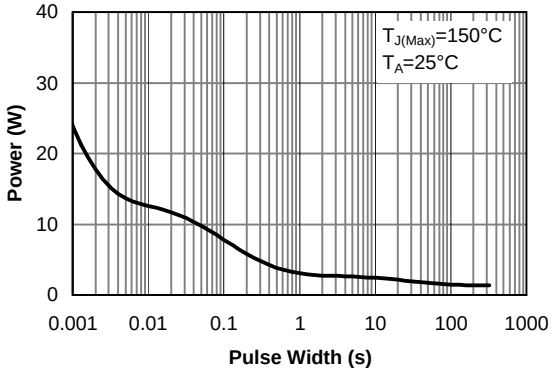


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

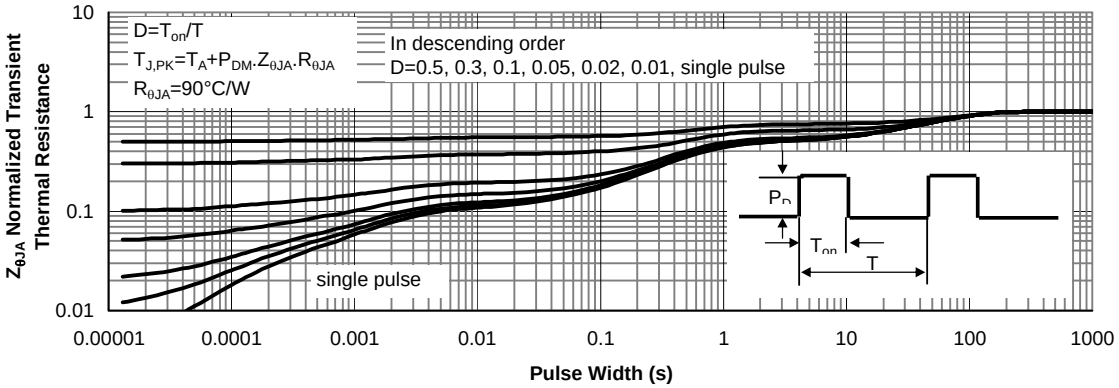


Figure 11: Normalized Maximum Transient Thermal Impedance